

WHAT IS CLAIMED IS:

1. A circuit, for use in testing an IC-module;
said circuit comprising:

a single transistor having a current channel
which is coupled in series with a first resistor between
5 a source voltage terminal and an output terminal;

said single transistor also having a control
lead, for enabling and disabling the flow of current thru
said current channel, which receives an input test
signal;

10 a second resistor which couples said output
terminal to a reference voltage terminal; and,

a socket which is structured to hold said IC-
module, having a test signal input terminal that is
coupled to said output terminal.

2. A circuit according to claim 1 wherein said first and second resistors have magnitudes which limit the square of said current thru said current channel, times said first and second resistors, to be less than
5 one-tenth of one watt.

3. A circuit according to claim 1 wherein said first resistor is connected directly to said source voltage terminal, and said current channel of said single transistor is connected directly to said output terminal.

4. A circuit according to claim 1 wherein said current channel of said single transistor is connected directly to said source voltage terminal, and said first resistor is connected directly to said output terminal.

5. A circuit according to claim 1 wherein said single transistor has a resistance through said current channel when said current is enabled which has a large tolerance, and said first and second resistors are
5 substantially larger in resistance and have a small tolerance.

6. A circuit according to claim 1 which further includes a variable voltage source which has an output that is coupled to said source voltage terminal.

7. A circuit according to claim 1 wherein the only coupling between said output terminal and said second resistor is a conductor.

8. A circuit according to claim 1 wherein the only coupling between said output terminal and said second resistor is a conductor in a series with an inductive filter.

9. A circuit according to claim 1 wherein the only coupling between said output terminal and said test signal input terminal on said socket is a conductor and an input to one digital multiplexor.

10. A circuit according to claim 1 wherein the only coupling between said output terminal and said test signal input terminal on said socket is a conductor and an input to one analog multiplexor.

11. A circuit according to claim 1 wherein said single transistor is an N-channel field effect transistor.

12. A circuit according to claim 1 wherein said single transistor is a P-channel field effect transistor.